Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/629,028	YI ET AL.	
Examiner	Art Unit	
A Devter Tughang	3729	

SEARCHED				
Class	Subclass	Date	Examiner	
29	603.13 603.14 603.08	3/3/2006	ADT	
360	322 324.2			
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427	523			
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204	192.1			
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
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